Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (IITO-220) internally insulated plastic package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This "series CT" triac will commutate the full RMS current at the maximum rated junction temperature without the aid of a snubber where "high junction operating temperature capability" is required.

2. Features and benefits

- 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- High immunity to false turn-on by dV/dt
- High junction operating temperature capability (T_{i(max)} = 150 °C)
- High voltage capability
- · Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only
- Internally insulated package
- Isolated mounting base with 2500 V (RMS) isolation

3. Applications

- · Electronic themostats (heating and cooling)
- · High power motor controls e.g washing machine and vacuum cleaners
- · Rectifier-fed DC inductive loads e.g DC motors and solenoids
- · Refrigeration and air conditioning compressors

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit					
Absolute	Absolute maximum rating								
V_{DRM}	repetitive peak off-state voltage		800	V					
$I_{T(RMS)}$	RMS on-state current	full sine wave; $T_{mb} \le 112 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3	16	A					
I _{TSM}	non-repetitive peak on- state current	full sine wave; t_p = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	160	A					
		full sine wave; t_p = 16.7 ms; $T_{j(init)}$ = 25 °C	176	Α					
T _j	junction temperature		150	°C					

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics				'	
l _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G + T_i = 25 \text{ °C; } Fig. 7$	-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	35	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	40	mA
V _T	on-state voltage	I _τ = 20 A; T _j = 25 °C; <u>Fig. 10</u>	-	-	1.5	V
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit	1000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; $(V_{DM}$ = 67% of V_{DRM}); gate open circuit	500	-	-	V/µs
dl _{com} /dt rate of change of commutating current		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; gate open circuit;}$ snubberless condition	12	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		T2—T1
2	T2	main terminal 2		G sym051
3	G	gate		symoon
mb	n.c	mounting base; isolated	Ĺ <u>.</u>	
			$\bigcup_{1}\bigcup_{2}\bigcup_{3}$	
			IITO-220 (SOT78D)	

6. Ordering information

Table 3. Ordering information

Type number	Package	Orderable part number	Packing	Small packing	Package	Package			
	name		method	quantity	version	issue date			
BTA316Y-800CT	IITO-220	BTA316Y-800CTQ	Tube	50	IITO-220E	15-Dec-2017			

7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA316Y-800CT	BTA316Y-800CT

BTA316Y-800CT

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V_{DRM}	repetitive peak off-state voltage		800	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{mb} \le 112^{\circ}C$; <u>Fig. 1</u> ; <u>Fig. 2</u> ; <u>Fig. 3</u>	16	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; t_p = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	160	А
		full sine wave; t_p = 16.7 ms; $T_{j(init)}$ = 25 °C	176	А
I ² t	I ² t for fusing	t _p = 10ms; sine wave	128	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 150mA	100	A/µs
I _{GM}	peak gate current		2	А
P _{GM}	peak gate power		5	W
P _{G(AV)}	average gate power	over any 20 ms period	0.5	W
T _{stg}	storage temperature		-40 to 150	°C
T _j	junction temperature		150	°C

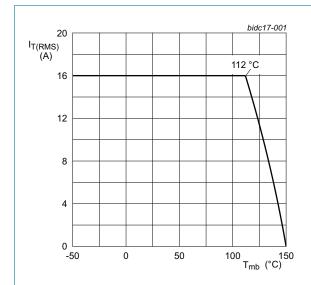


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

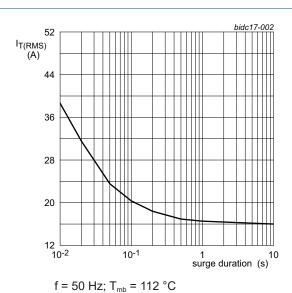


Fig. 2. RMS on-state current as a function of surge duration; maximum values

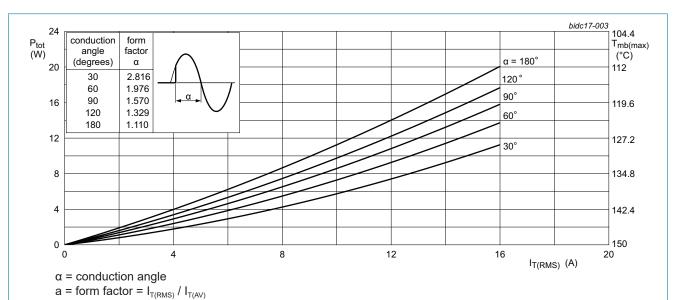


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

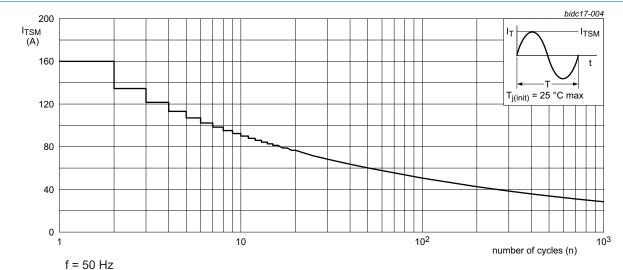
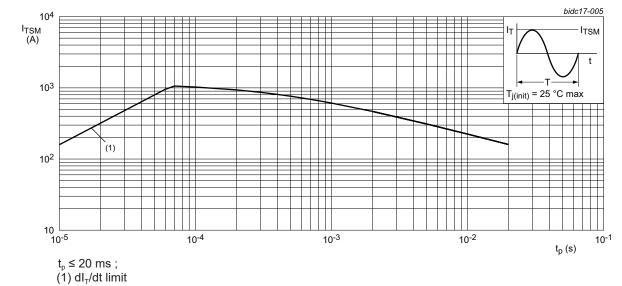


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



9. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	-	1.9	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	in free air	-	60	-	K/W

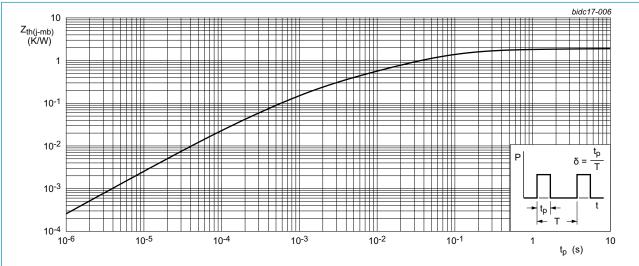


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Isolation characteristics

Table 6. Isolation characteristics

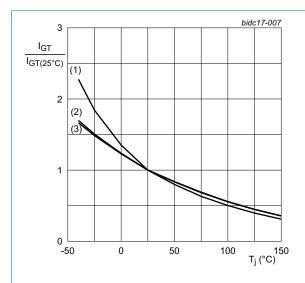
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C _{isol}	isolation capacitance	from cathode to external heatsink	-	10	-	PF

11. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics		·			
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	35	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	35	mA
L	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } Fig. 8$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	70	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	50	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	40	mA
V _T	on-state voltage	I _T = 20 A; T _j = 25 °C; <u>Fig. 10</u>	-	-	1.5	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.8	1	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C};$ Fig. 11	0.2	0.45	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C	-	-	5	μA
		V _D = 800 V; T _j = 150 °C	-	-	2	mA
Dynamic o	characteristics		<u> </u>		'	
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit	1000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit	500	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 16 A; dV_{com}/dt = 20 V/µs; gate open circuit; snubberless condition	12	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 16 \text{ A}; $ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; gate open circuit}$	15	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$	20	-	-	A/ms

bidc17-008



(1) T2- G-(2) T2+ G-

(3) T2+ G+

3 I_L
1 I_{L(25°C)}
2
1
0
-50
0
50
100
T_j (°C)

Fig. 8. Normalized latching current as a function of junction temperature



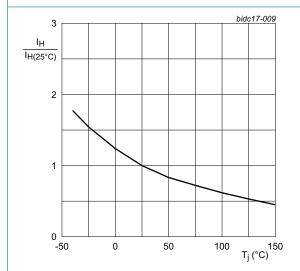
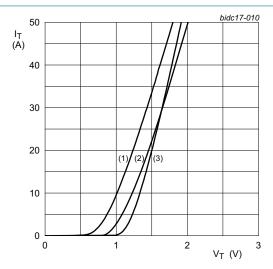


Fig. 9. Normalized holding current as a function of junction temperature



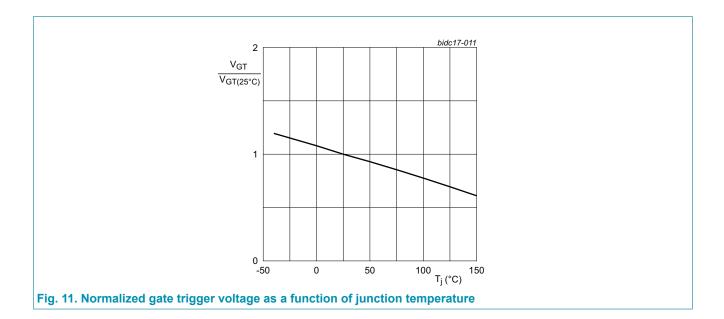
 $V_o = 1.009 \text{ V}; R_s = 0.0216 \Omega$

(1) T_i = 150 °C; typical values

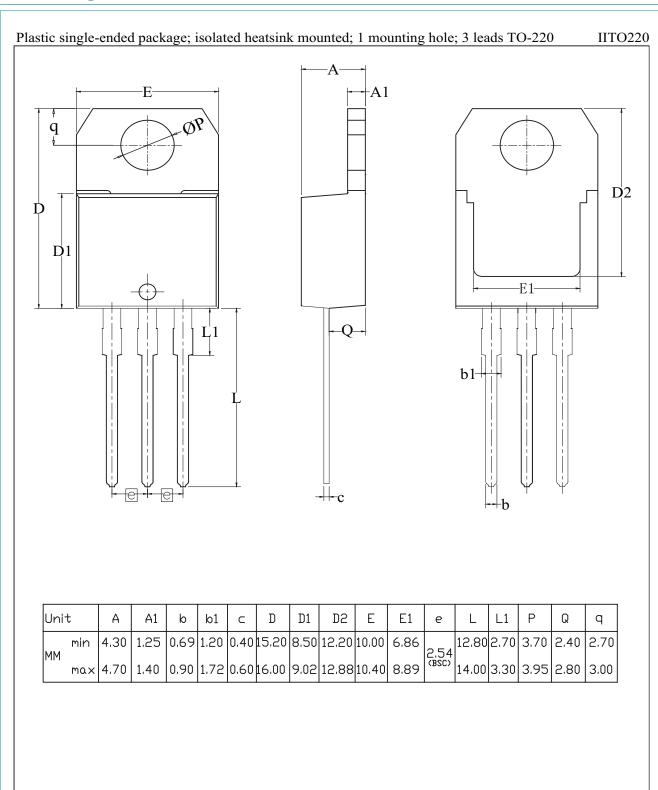
(2) T_j = 150 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



12. Package outline



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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For more information, please visit: http://www.ween-semi.com
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